Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/783,250	PAL ET AL.
Examiner	Art Unit
Chuck Kendall	2192

	SEARCHED				
JEARCHED					
Class	Subclass	Date	Examiner		
717	124-137	6/2/2005	ск		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Consult Wei, XP 2122	4/19/2005	ск
East Search (USPGPUB,IBM,DERWENT,JPO,EP O, USPATENT)	6/2/2005	ск
	,	